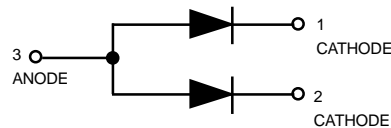
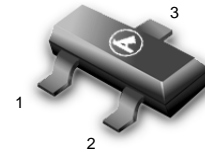


Monolithic Dual Switching Diode Common Anode



BAW56LT1



CASE 318-08, STYLE12
SOT- 23 (TO-236AB)

MAXIMUM RATINGS (EACH DIODE)

Rating	Symbol	Value	Unit
Reverse Voltage	V_R	70	Vdc
Forward Current	I_F	200	mAdc
Peak Forward Surge Current	$I_{FM(surge)}$	500	mAdc

THERMAL CHARACTERISTICS

Characteristic	Symbol	Max	Unit
Total Device Dissipation FR- 5 Board (1) $T_A = 25\text{ }^\circ\text{C}$	P_D	225	mW
Derate above $25\text{ }^\circ\text{C}$		1.8	mW/ $^\circ\text{C}$
Thermal Resistance, Junction to Ambient	$R_{\theta JA}$	556	$^\circ\text{C/W}$
Total Device Dissipation Alumina Substrate, ⁽²⁾ $T_A = 25\text{ }^\circ\text{C}$	P_D	300	mW
Derate above $25\text{ }^\circ\text{C}$		2.4	mW/ $^\circ\text{C}$
Thermal Resistance, Junction to Ambient	$R_{\theta JA}$	417	$^\circ\text{C/W}$
Junction and Storage Temperature	T_J, T_{stg}	-55 to +150	$^\circ\text{C}$

DEVICE MARKING

BAW56LT1 = A1

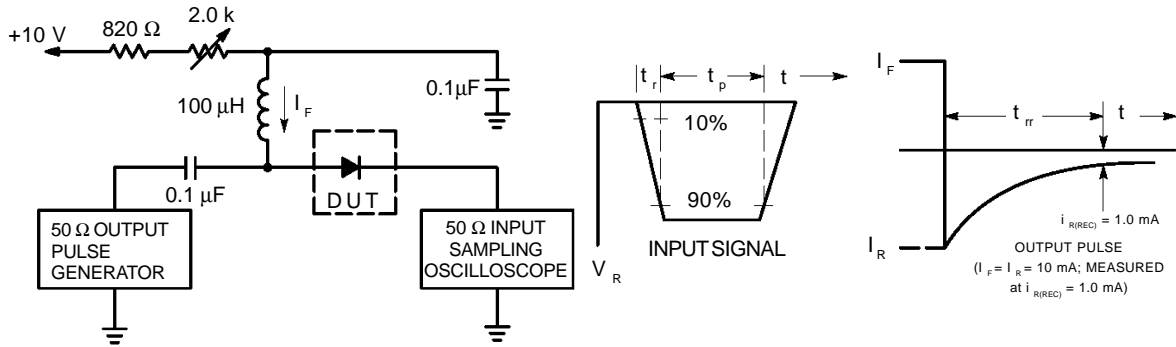
ELECTRICAL CHARACTERISTICS ($T_A = 25\text{ }^\circ\text{C}$ unless otherwise noted) (EACH DIODE)

Characteristic	Symbol	Min	Max	Unit
OFF CHARACTERISTICS				
Reverse Breakdown Voltage ($I_{(BR)} = 100\text{ }\mu\text{Adc}$)	$V_{(BR)}$	70	–	Vdc
Reverse Voltage Leakage Current ($V_R = 25\text{ Vdc}, T_J = 150\text{ }^\circ\text{C}$)	I_R	–	30	μAdc
($V_R = 70\text{ Vdc}$)		–	2.5	
($V_R = 70\text{ Vdc}, T_J = 150\text{ }^\circ\text{C}$)		–	50	
Diode Capacitance ($V_R = 0, f = 1.0\text{ MHz}$)	C_D	–	2.0	pF
Forward Voltage ($I_F = 1.0\text{ mAdc}$)	V_F	–	715	mVdc
($I_F = 10\text{ mAdc}$)		–	855	
($I_F = 50\text{ mAdc}$)		–	1000	
($I_F = 150\text{ mAdc}$)		–	1250	
Reverse Recovery Time ($I_F = I_R = 10\text{ mAdc}, I_{R(REC)} = 1.0\text{ mAdc}$) (Figure 1) $R_L = 100\Omega$	t_{rr}	–	6.0	ns

1. FR-5 = 1.0 x 0.75 x 0.062 in.

2. Alumina = 0.4 x 0.3 x 0.024 in. 99.5% alumina.

BAW 5 6 IT 1



- Notes: 1. A 2.0 kΩ variable resistor adjusted for a Forward Current (I_F) of 10mA.
- 2. Input pulse is adjusted so $I_{R(\text{peak})}$ is equal to 10mA.
- 3. $t_p \gg t_{rr}$

Figure 1. Recovery Time Equivalent Test Circuit

CURVES APPLICABLE TO EACH CATHODE

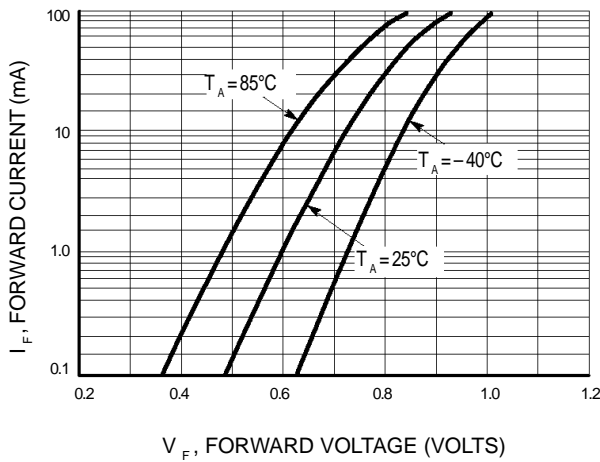


Figure 2. Forward Voltage

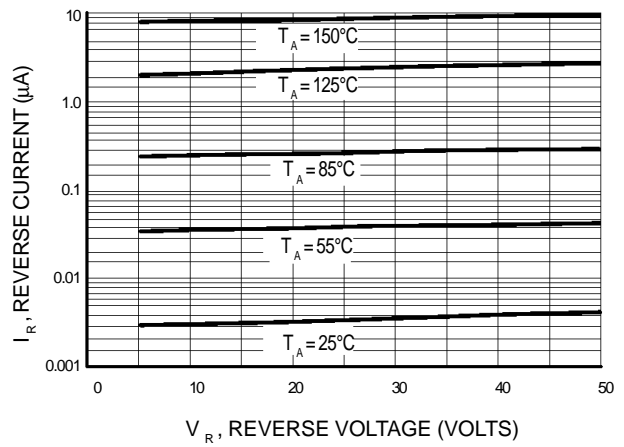


Figure 3. Leakage Current

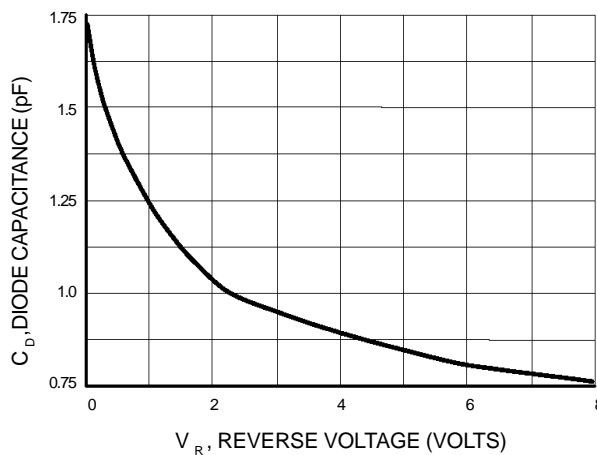


Figure 4. Capacitance